Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/605,202	BAXTER, JOHN F.
Examiner	Art Unit
Zhiyu Lu	2618

SEARCHED					
Subclass	Date	Examiner			
3.01 3.02 426 427	7/22/2005	ZL			
	7/22/2005	ZL			
search	2/24/2006	ZL			
	3.01 3.02 426 427	Subclass Date 3.01 3.02 426 427 7/22/2005			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
		 			
		<u> </u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventorship search	7/21/2005	ZL	
Consulted with Lee Nguyen	7/21/2005	ZL	
Consulted with Rafael Perez	7/25/2005	ZL	
Updated search with keywords	2/24/2006	ZL	